

# ACCURACY-ENERGY TRADE-OFF WITH DYNAMIC ADEQUATE OPERATORS

MPSoC 2017 | Anca Molnos | 06/07/2017



- **Context: adequate/approximate computing**
- **Hardware**
  - Design methodology for dynamic–accuracy operators
- **Software use-case**
  - Trading sharpness with energy consumption in an autofocus application
- **Conclusions**

## WHY APPROXIMATE COMPUTING

Many emerging applications are error tolerant (or error resilient)

- E.g., human perception, noisy input, recognition/classification algorithms



- **Opportunity: increased performance or reduced energy consumption without significant impact in the quality of result**
  - Probabilistic computing, imprecise computing, approximate computing, ...
  - **Adequate computing** = run-time accuracy-energy trade-off
    - Accommodate time-varying error tolerance
  - This idea may be applied at various levels: algorithm, data encoding, arithmetic precision, **operator implementation**, ...

## 1. Approximate/inexact circuits:

- Mostly adders and multipliers
- *Kyaw, Goh and Yeo, EDSSC'10, Huang, Lach and Robins, DAC'12, Farshchi, Saeed and Fakhraie, CADs'13, Jiang, Han and Lombardi, GLSVLSI'15, Bhardwaj, Mane and Henkel, Int'l Symp. on QED'15, A Lingamneni, et al. TECS'13, etc.*

## 2. Approximate synthesis:

- Generalization of the previous techniques to any netlist
- *Shin and Gupta, ATS'08, Venkataramani et al, DAC'12, Miao, Gerstlauer and Orshansky, ICCAD'13, etc.*

## 3. Quality-configurable circuit architectures:

- Voltage over-scaling + error correction
- Adders, multipliers, etc.
- *De la Guya Solaz, Han, Conway, IEEE Trans. On CAS'11, Kahng and Kang, DAC'12, Ye et al, ICCAD'13, Liu, Han and Lombardi, DATE'14, etc.*
- Voltage scalable meta-functions.
- *Mohapatra, Chippa, Raghunathan and Roy, DATE'11*

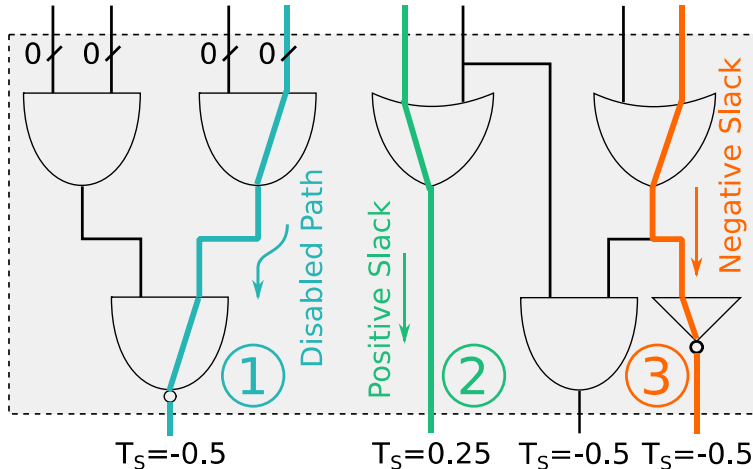
## 4. Dynamic Voltage and Accuracy Scaling (DVAS):

- Use *technological knobs* only (no design modifications)
- Reduce bit-width of input operands (LSB bits to 0) and voltage down-scaling
- *Moons and Verhelst, ISLPED'15, etc.*

# DYNAMIC ACCURACY OPERATORS

- Limitation of DVAS:**

- In standard ASIC implementation flow: most timing paths have a delay close to the critical one
- Lower VDD  $\rightarrow$  the entire operator is slowed-down.



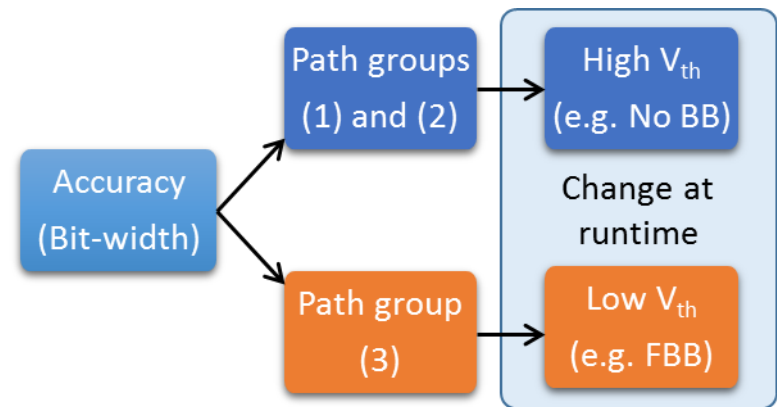
**Need fine-grain power/delay tuning!**

- One possibility: multi-VDD**

- Requires level shifters
- Excessive power overhead for an FU

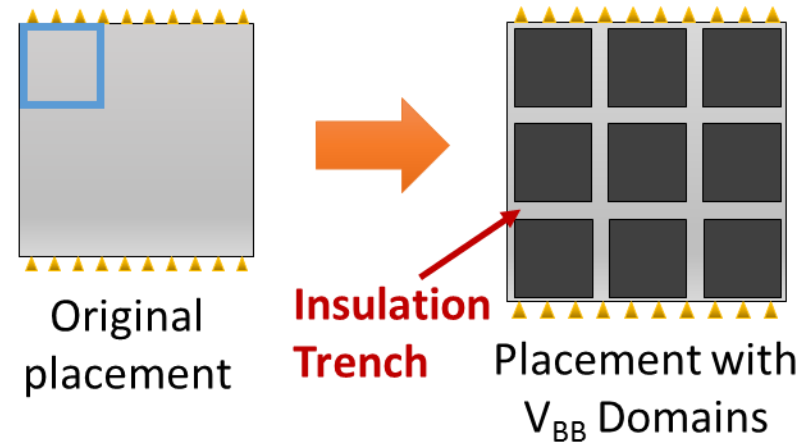
- Alternative:**

- Combine DVAS with FDSOI's back bias scaling.**
- Fine-grain threshold voltage ( $V_{th}$ ) tuning



# CIRCUIT PARTITIONING IN $V_{BB}$ DOMAINS

- **Proposed partitioning:** regular tiling
  - Start from placed design
  - Divide the area in N identical  $V_{BB}$  domains
  - Assign each cell to the “closest” domain



- **Pros:**
  - Regularity of design
  - **Easy to incorporate in an EDA flow**
  - Minimal displacement of cells w.r.t. a placement with standard constraints  
→ **Minimal timing, area and power overheads at maximum bit-width.**
- **Cons:**
  - For a given accuracy, if a single domain contains cells that require different  $V_{th}$  values, all cells must receive the lowest  $V_{th}$
  - Leakage overhead!

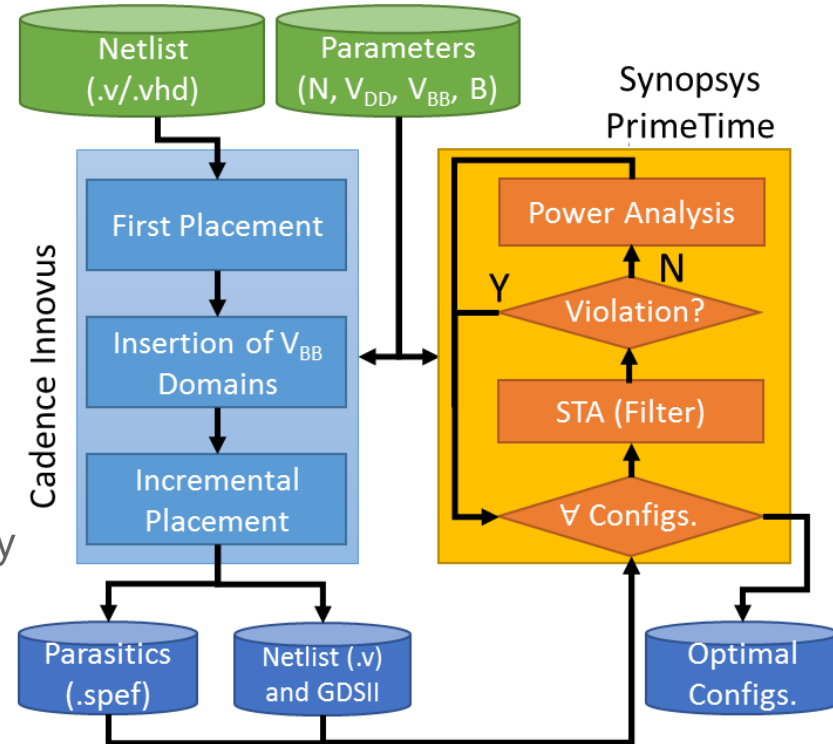
# IMPLEMENTATION FLOW – 2 PHASES

## Implementation Phase

- Partition circuit in VBB domains using regular tiling.
- Incremental placement:
  - Insert well-taps
  - Fix possible constraints violations in nominal operating conditions due to cell displacement.

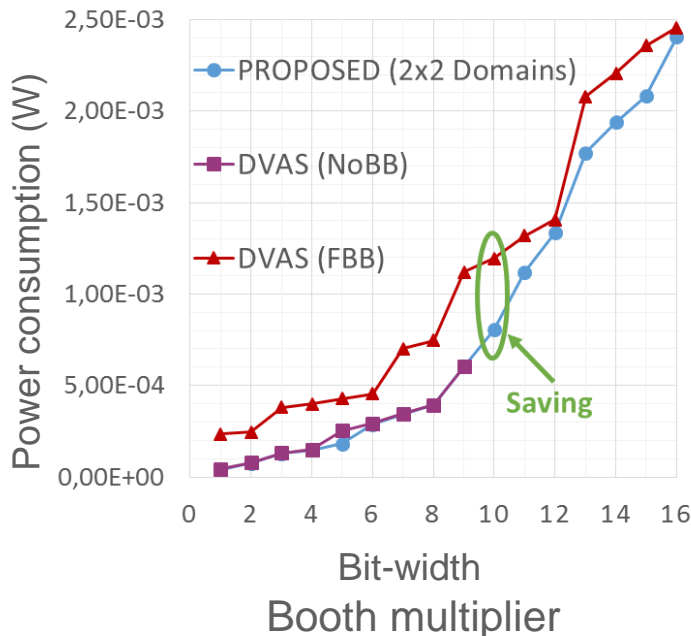
## Analysis&Optimization Phase

- Exhaustive exploration of all possible configurations of Accuracy,  $V_{BB}$ , and possibly global  $V_{DD}$
- Static Timing Analysis (STA) to prune unfeasible configurations (timing violations)
- Power analysis on feasible configurations
- Many configurations (thousands), but fast analysis. Feasible for  $< 10-15$   $V_{BB}$  domains

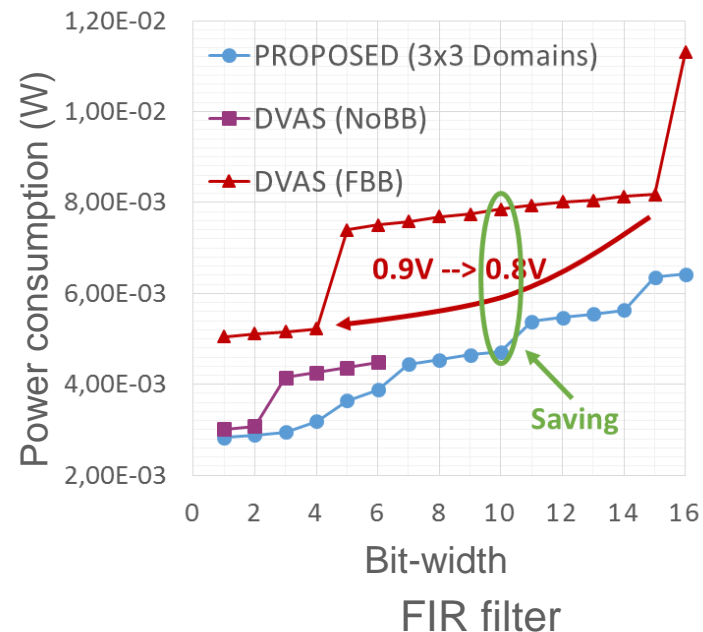


## EXPERIMENTAL RESULTS

- Implemented several operators circuits (16-bit fixed-point)
  - Booth multiplier, FFT butterfly unit, 30-tap FIR filter
  - Technology: 28nm UTBB FDSOI from ST Microelectronics
- Operating conditions:
  - $V_{DD} = [0.6V, 0.7V, \dots 1.0V]$
  - Forward BB:  $V_{BB} = \pm 1.1V$  (N-Well/P-Well)
  - Nominal condition (for 1st placement): 1.0V + FBB in all domains.



32.7% Saving w.r.t. DVAS @ 10-bit accuracy  
Area overhead: 15%



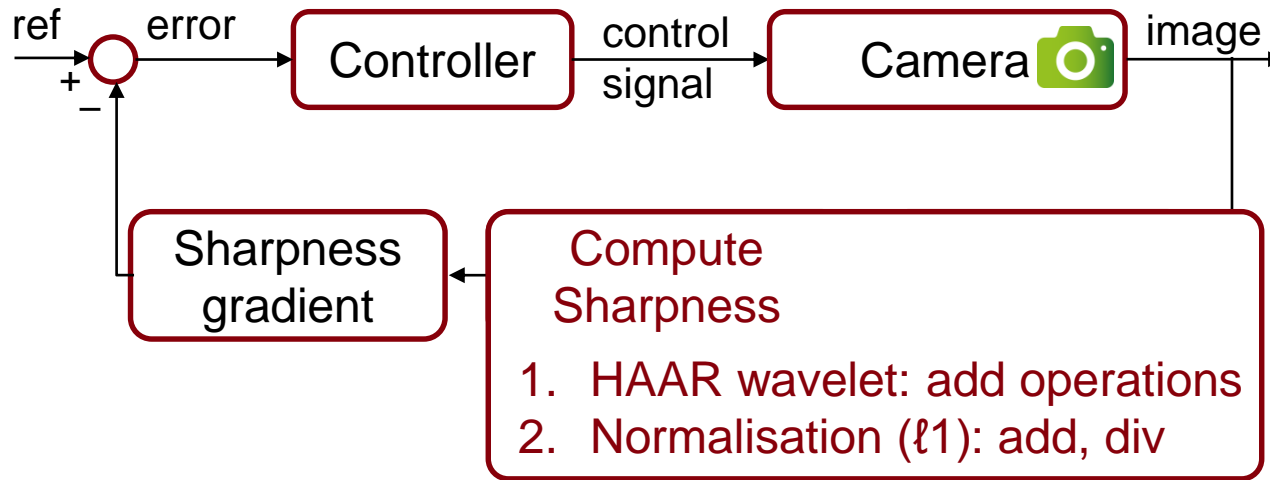
39.9% Saving w.r.t. DVAS @ 10-bit accuracy  
Area overhead: 16%



- Context: adequate/approximate computing
- Hardware
  - Design methodology for dynamic–accuracy operators
- **Software use-case**
  - Trading sharpness with energy consumption in an autofocus application
- Conclusions

# LENS AUTO-FOCUS USE CASE

- **Auto-focus control loop on a region of interest (ROI)**
  - adaptive, integral controller
  - sharpness  $\rightarrow$  modified Haar-wavelet and normalisation
    - only the horizontal and vertical high-pass components of the transform are taken into the consideration
    - simple computation (**many addition operations** and few division operation)
  - *Zarudniev et al. NEWCAS'15*

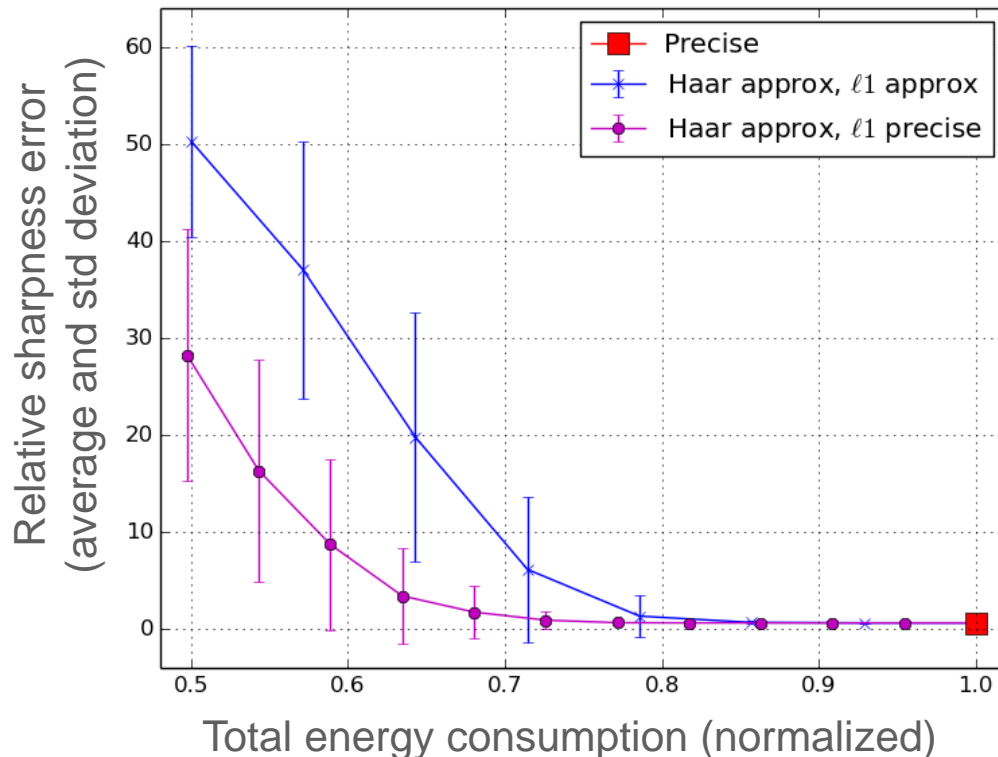


**Study: impact of adequate addition operations**

*N. Gonthier et. al "Trading sharpness with energy consumption in a lens autofocus application", in Workshop on Approximate Computing, ESWEK, 2016.*

# EXPERIMENTAL RESULTS

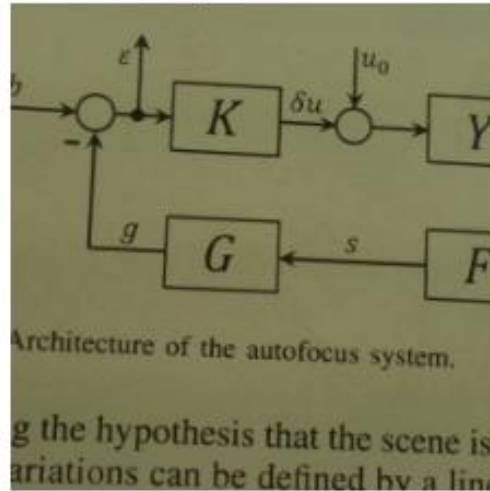
- **Baseline: precise additions, energy level = 1**
- **39 images, ROI with 256x256 pixels → 17K addition operations**
  - 16K in Haar transform
  - 1K in norm  $\ell_1$
- **2 cases**
  - all operations (Haar wavelet and normalization) are approximate
  - additions in the Haar wavelet are approximate and the normalization is precise



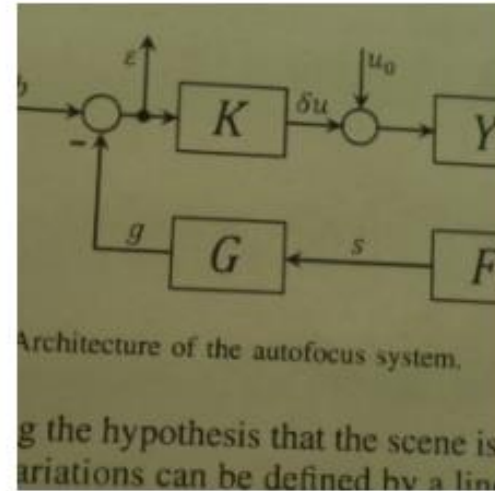
30% reduction on energy → sharpness degradation of only 2%.

## EXAMPLE OF SHARPNESS DEGRADATION

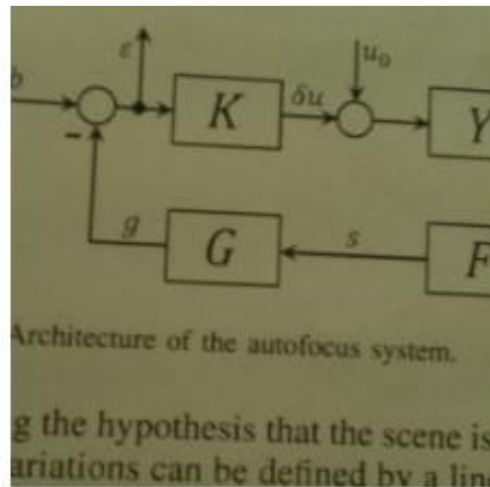
Maximum sharpness



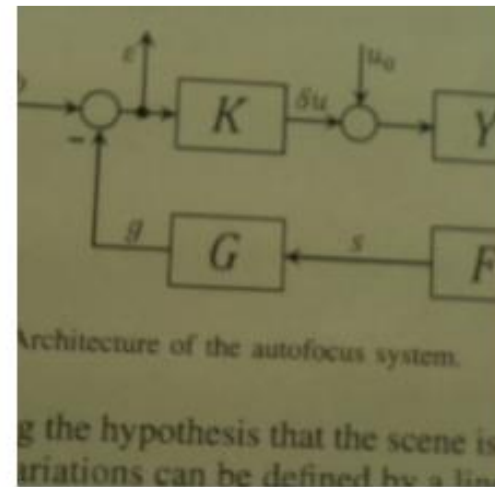
Relative sharpness error 10%



Relative sharpness error 25%



Relative sharpness error 50%



- **Summary and perspectives:**

- Back-Bias is an effective knob for fine-grain delay/power tuning in quality-configurable functional units.
  - First ever application of Back-Biasing to quality-configurable systems (to our knowledge).
  - Easy to integrate with EDA flows
  - Many avenues for optimization: alternative partitioning techniques (irregular tiling), avoid exhaustive analysis of all  $V_{DD}$ ,  $V_{BB}$ , and accuracy combinations, ...
  - Compare with emerging multiple-precision fixed and floating point approaches
  - Approximate/adequate memory and storage
- Energy gain potential for a small loss in final image sharpness in auto-focus use-case.
  - More applications to be investigated

- **Challenges at application level**

- Analysis/programming/compiler support for adequate operations
  - Methods to find sensitive application parts
  - Analysis of error propagation for large applications
- Algorithmic changes for better error-resilience

## ACKNOWLEDGEMENTS

- Yves Durand, CEA-Leti, France
- Edith Beigne, CEA-Leti, France
- Daniele Jahier Pagliari, Politecnico di Torino, Italy
- Massimo Poncino, Politecnico di Torino, Italy

# Thank you!

---

**Leti, technology research institute**  
Commissariat à l'énergie atomique et aux énergies alternatives  
Minatec Campus | 17 rue des Martyrs | 38054 Grenoble Cedex | France  
[www.leti.fr](http://www.leti.fr)

